Search Notes

Ocarch Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/796,175	ARAKAWA ET AL.	
Examiner	Art Unit	
Yicun Wu	2165	

SEARCHED			
Class	Subclass	Date	Examiner
707	1,2,3,4 5,6,7,8 9,10, 100	7/20/05	\
	104.1		
711	112 114		
L	147154		
714	6, 13	<u> </u>	
-			

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
		<u> </u>	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
inventor search (double patenting) uspto uspgpub usocr epo jpo ibmtech derwent	7.120/05	1
acm ieee citeseer internet Search stratagy attached		
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